

- Pending
- Active
- L21: (14) ("6730575" "6514842" "6377070" "5959465" "5488612" "4939559" "4688078").pn.
- L22: (13) 09043134
- Failed
- Saved

- (81) ((asymmetri\$4 differen\$3) near9 tunnel\$3) with (metal perovskite superlattice)
- (12804) (float\$3 adj gate) same (control adj gate)
- (1) ((asymmetri\$4 differen\$3) near9 tunnel\$3) with (metal perovskite superlattice)
- (5) ((asymmetri\$4 differen\$3) near9 tunnel\$3) with (metal perovskite superlattice)
- (273) ((asymmetri\$4 differen\$3) near9 tunnel\$3) with (oxide)
- (203) ((float\$3 adj gate) same (control adj gate)) and ((asymmetri\$4 differen\$3) near9 tunnel\$3...)
- (12) ((asymmetri\$4 differen\$3) near9 tunnel\$3) with (transition\$3)
- (0) 10/081818
- (1632) afd (atomic adj layer adj deposit\$3)
- (22231) float\$3 adj gate
- (32840) control adj gate
- (13057) (float\$3 adj gate) same (control adj gate)
- (0) ((float\$3 adj gate) same (control adj gate)) same (afd (atomic adj layer adj deposit\$3))
- (11) ((float\$3 adj note leave (control adj note)) and (afd (atomic adj layer adj deposit\$3)))

Default operator:	OR	DBs:	US, PGPUB, EPO, ICRWENT, IBM, TDB	P: Plurals	H: Highlight all hit terms initially
09043134					
<i>Oct 2004</i>					

#	Inventor(s)	Document ID	Issue Date	Page	Title	Current OR	Current XRef
1	<input checked="" type="checkbox"/> Bhattacharyya, Arup	US 20030151948 A1	20030814	33	Asymmetric band-gap engineered nonvolatile memory device	365/185.18	
2	<input checked="" type="checkbox"/> Bhattacharyya, Arup	US 6784480 B2	20040831	32	Asymmetric band-gap engineered nonvolatile memory device	257/314	257/318
3	<input checked="" type="checkbox"/> Eldridge, Jerome M. et al.	US 20040158863 A1	20040819	38	Graded composition metal oxide tunnel barrier interpoly insulators	257/239	
4	<input checked="" type="checkbox"/> Eldridge, Jerome M. et al.	US 20030048666 A1	20030313	39	Graded composition metal oxide tunnel barrier interpoly insulators	365/185.28	257/E21.683;
5	<input checked="" type="checkbox"/> Eldridge, Jerome M. et al.	US 20030045082 A1	20030306	33	Atomic layer deposition of metal oxide and/or low asymmetrical tunnel barrier interpoly insulators	439/593	257/E21.683;
6	<input checked="" type="checkbox"/> Forbes, Leonard	US 20040190342 A1	20040930	25	DRAM cells with repressed floating gate memory, low tunnel barrier interpoly insulators	365/185.25	257/E27.103;
7	<input checked="" type="checkbox"/> Forbes, Leonard	US 20040168145 A1	20040826	33	Service programmable logic arrays with low tunnel barrier interpoly insulators	716/17	326/47
8	<input checked="" type="checkbox"/> Forbes, Leonard	US 20040160830 A1	20040819	27	DRAM cells with repressed floating gate memory, low tunnel barrier interpoly insulators	365/185.28	
9	<input checked="" type="checkbox"/> Forbes, Leonard	US 6754108 B2	20040622	26	DRAM cells with repressed floating gate memory, low tunnel barrier interpoly insulators	365/185.25	365/149;
10	<input checked="" type="checkbox"/> Forbes, Leonard et al.	US 20040164342 A1	20040826	31	Integrated circuit memory device and method	257/316	365/185.08;

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Ready

OK